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**16 High speed image data compression processor for Advanced Land Observing Satellite (ALOS)**

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[\[Abstract\]](#)   [\[PDF Full-Text \(317KB\)\]](#)   IEEE CNF

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[\[Abstract\]](#) [\[PDF Full-Text \(233KB\)\]](#) IEEE CNF

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[Prev](#) [1](#) [2](#) [3](#) [4](#) [5](#) [Next](#)

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